





Trevor Smith Pico Technology



Physical layer validation of high-performance backplanes, connectors, cables and high speed serial data systems using a sampling oscilloscope



- Introduction
- Oscilloscope types, applications and costs
- Sampling oscilloscopes
- Signal Integrity Measurements
 - Frequency / Bit Rate / Jitter / Noise / Eye Analysis
- TDR / TDT Introduction
- Optical
- Questions



Critical Signal Integrity (SI) considerations for high speed digital designs

- PCB layout
- Backplane design
- Connectors
- External interfaces
- Component performance
- Compliance and interoperability with industry standards





Real-time Oscilloscopes



- Can capture single instantaneous or repetitive events
- 8-bit ADC resolution, but lower effective bits at high frequencies
- Deep buffer memory
- Advanced triggers & display modes to capture intermittent events
- Serial bus decoding
- Ideal for general use and fault diagnosis
- Real-time GS/s sampling is *expensive*: ~ \$200K for 20 GHz

Sampling Oscilloscopes



- Can capture cyclic signals & repeating patterns at steady data rate
- Short buffer memory
- Low sample rate
- Lower intrinsic jitter and noise
- Eye diagrams and mask testing
- Best choice for TDR/TDT
- Lower, but still significant cost: ~ \$50K for 20 GHz

PicoScope PC-based instruments







PicoScope 9300

- 20 GHz bandwidth
- 2 channels
- Built-in pattern generator
- Automated measurement tools and analysis of clock, data and eye diagrams mask testing
- Models with:
 - Clock recovery to 11.3 Gb/s
 - Differential TDR/TDT with 40 ps edge
 - Optical
- Low cost: 20 GHz for \$15K

Real-time Digital Oscilloscope





Real-time Digital Oscilloscope





Sampling Oscilloscope



'Analog bandwidth' is the maximum frequency that can pass through the front end of an oscilloscope





Choose a scope with enough bandwidth for the application:

- Signal transition time
- Signal clock or data rate
- Signal rise and fall time
- Signal narrowest pulse

Effects of too little bandwidth:

- Amplitude and timing errors
- Loss of high frequency aberrations and detail



Calculating bandwidth from data rate:

 3^{rd} Harmonic = $3 \times \frac{Bit rate}{2}$

 5^{th} Harmonic = 5 x <u>Bit rate</u> 2

Application example

PCIe R1.0a has a data rate of 2.5 Gbps (1.25 GHz frequency) Bandwidth required to see 5 harmonics is 1.25 GHz x 5 = 6.25 GHz





Sequential Sampling



- Data points are acquired sequentially from many cycles to build one screen image
 - PicoScope 9300 sample rate is 1 MS/s, bandwidth is 20 GHz



 Convert high-speed signal (GHz) to a low-frequency copy (kHz)



PicoScope 9300 Front Panel





20 GHz 2 channels Clock Data Recovery: 11.3 Gb/s Differential TDR: 40 ps, 200 mV step (6 V, 65 ps step) USB & LAN interfaces PicoSample[™] 3 software

Making Basic Measurements





Comprehensive Measurements





Measure Scales						Auto Max Mid Min
	Current	Total Wfms	Minimum	Maximum	Mean	Std Deviation
Frequency (Ch1)	500 MHz	36905	498.3 MHz	501.3 MHz	499.9 MHz	367.6 kHz
Period (Ch1)	2 ns	36905	1.995 ns	2.007 ns	2 ns	1.471 ps
Rise Time (Ch1)	477.2 ps	36905	453.6 ps	484.7 ps	469.5 ps	4.347 ps
Pos Jitter p-p (Ch1)	26.53 ps	36856	6.633 ps	26.53 ps	21.27 ps	2.888 ps

Comprehensive Measurements



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🔊 View Defi	ned Parameters	Period (Ch1)	2 ns	36905	1.995 ns	2.007 n	IS	2 ns	1.471 ps	
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Clear All I	vieasurements	Pos Jitter p-p (Ch1)	26.53 ps	36856	6.633 ps	26.53 p	IS	21.27 ps	2.668 ps	

Vertical Histogram





Histogram Scales			Auto Max Mid Min
Scale = 78.2 khits/	Peak Hits = 390.801 khits	Std Deviation = 266.17 mV	
Offset = 0 hits	Pk-Pk = 757.62 mV	Mean ± 1 StdDev = 52.678 %	
Hits in Box = 48.7853 Mh	its Median = 261.28 mV	Mean ± 2 StdDev = 100 %	
Waveforms = 110374 Wfn	ns Mean = 197.44 mV	Mean ± 3 StdDev = 100 %	
Min = -117.53 mV	Max-Max = 706.87 mV	Max = 640.09 mV	

Horizontal Histogram





Look into My Eyes!





Automatic eye measurements and data

9.95 Gb/s with 10 Gb/s Mask

Eye-line Triggering

TDR/TDT

- Differential TDR
- 65 ps, 6 V step generator built in
- 40 ps, 200 mV external generator
- Plot voltage, impedance or reflection coefficient against time or distance

Optical

- 9.5 GHz precision O/E converter
- SM & MM connectors
- 750 to 1650 nm
- Automatic measurements
 - Extinction ratio
 - S/N ratio
 - Eye height & width

PicoScope 9300 Applications

Summary

9300 Sampling Oscilloscopes

- Economical 20 GHz solution
- Broad range of SI measurements
- Eye diagram analysis
- Mask testing for production
- Support for popular industry standards
 - PCIe, SATA, SONET/SDH, Ethernet, RapidIO, InfiniBand . . . plus user-defined
- TDR/TDT for validation of cables, connectors, interconnects etc.
- Optical
- Signal & timing analysis, testing and design of high-speed digital communication systems, network analysis, & semiconductor testing